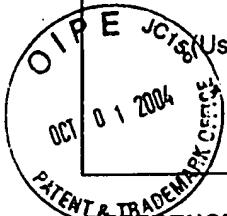


FORM PTO-1449 (Modified)		ATTY. DOCKET NO.	SERIAL NO.
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT(S) INFORMATION DISCLOSURE STATEMENT		02EK-105598	10/808,665
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APPLICANT: Lidu Huang, et al.			
FILING DATE: March 24, 2004		GROUP ART UNIT: 2877	



REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	Class	Subclass	Filing Date If Appropriate	
KG	A1	6,504,966	01/07/2003	Kato et al.	385	16	
	A2						
	A3						
	A4						

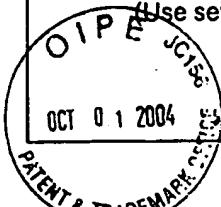
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'N	
						yes	no
	B						
	B						

OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)		
KG	C1	"Silica Integrated Optical Circuits", edited by H. M. Presby, Section 2 "Fabrication", SPIE Milestone Series, vol. MS 125, pp. 43-149, 1996
KG	C2	T. Fukano and I. Yamoguchi, "Simultaneous measurement of thickness and refractive indices of multilayers by a low-coherence confocal interference microscope", Opt. Lett., vol. 21, pp. 1942-1944, 1996
KG	C3	G. J. Veldhuis, L.E. W. van Veen and P. V. Lambeck, "Integrated optical refractometer based on waveguide bend loss", IEEE J. Lightwave Technol., vl. 17, pp. 857-864, 1999
KG	C4	D. C. Yin and Y. Inatomi, "Measurement of refractive index of GaP crystal over a large temperature range using interferometry", Cryst. Res. Technol., vol. 35, pp. 221-228, 2000
KG	C5	T. Dennis, E. M. Gill and S. L. Gilbert, "Interferometric measurement of refractive-index change in photosensitive glass", Appl. Optics, vol. 40, pp. 1663-1667, 2001
KG	C6	O. M. Efimov, L. B. Glebov and H. P. Andre, "Measurement of the induced refractive index in a photothermorefractive glass by a liquid-cell shearing interferometer", Appl. Optics, vol. 41, pp.1864-1870, 2002

EXAMINER	DATE CONSIDERED
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REFERENCE DESIGNATION
U.S. PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	NAME	Class	Subclass	Filing Date If Appropriate
	A						
	A						
	A						

FOREIGN PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'N	
							yes	no
	B							
	B							

OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

KG	C7	A. L. Glebov, L. Huang, S. Aoki, M. G. Lee and K. Yokochi, "Two dimensional microlens arrays in silica-on-silicon planar lightwave circuit technology", Journal of Microlithography, Microfabrication, & Microsystems, vol 2, no. 4, pp. 309-318, 2003
KG	C8	Metricom Corp., "Model 2010 Prism Coupler Application Notes Measuring Index Anisotropy of Free-Standing Polymer Films," www.metricom.com/applic6.htm , 6/29/2004
KG	C9	Brother Gregory Investigates, "Measuring Refractive Index," www.brooklyn.cuny.edu/bc/ahp/CellBio/ReflIndex/RI.Main.html , 6/30/2004
	C10	
	C11	
	C12	

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